



Organisation Internationale de Métrologie Légale

International Organization of Legal Metrology

International Organisation of Legal Metrology (OIML) Update

IECEX Management Committee Meeting
Dubai, 26-27 September 2019

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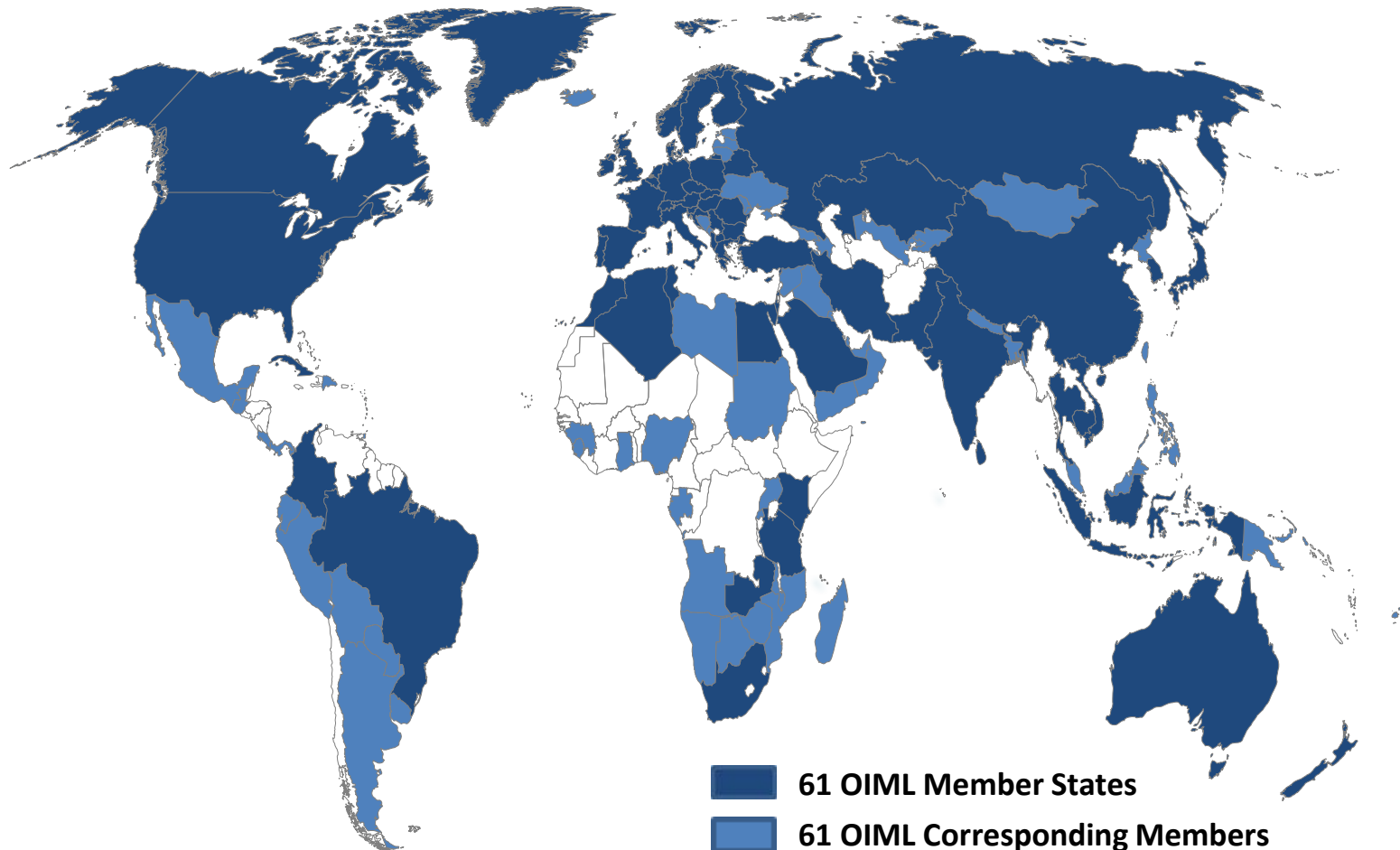
The OIML

- Intergovernmental treaty organization, established in 1955
- International standards setting organization under the terms of the WTO/TBT Agreement
- **The mission of the OIML is to:**
“Enable economies to put in place **effective legal metrology infrastructures** that are mutually compatible and internationally recognized, **for all areas** for which **governments** take responsibility, such as those which **facilitate trade, establish mutual confidence** and **harmonize the level of consumer protection** worldwide.”





OIML Membership





Technical Activities

Technical work

- 18 Technical Committees (TCs)
- 45 Sub Committees (SCs)
- 49 Project Groups

Outcome

- over 100 Recommendations
- 27 Documents
- 14 Basic Publications
- 2 Vocabularies
- 21 Guides





Current OIML Priorities

- On-going technical activities
- Implementation, evolution and promotion of the OIML Certification System (OIML-CS)
- Meeting the needs of Countries and Economies with Emerging Metrology Systems (CEEMS)
- Cooperation with other organizations to promote metrology as an important part of a sound quality infrastructure (QI) of a modern economy - INetQI
- Upcoming: Metrology for Digitization of Economy and Society
- e-Learning: concept development for the OIML website





OIML Certification System (OIML-CS)



- Launched on 1 January 2018
- Replaced the "Basic" Certificate System and OIML Mutual Acceptance Arrangement (MAA)
- OIML B 18:2018 Framework for the OIML Certification System (OIML-CS)





Principles of the OIML-CS

- Aims to **facilitate**, **accelerate** and **harmonize** work of **national and regional bodies** that are responsible for **type evaluation** and **type approval** of measuring instruments subject to **legal metrological control**
- It is a **voluntary** system and OIML Member States and Corresponding Members are free to participate
- Signing a **Declaration** commits, in principle, the signatories to **abide by the rules** of the OIML-CS



Objectives of the OIML-CS

- Promote **global harmonization**, uniform interpretation and implementation of legal metrological requirements for measuring instruments
- Avoid **unnecessary re-testing** when obtaining national type evaluations ... while achieving and maintaining confidence in the results in support of facilitating global trade of instruments
- Establish rules and procedures for fostering **mutual confidence** in the results of type evaluations



Overview of the OIML-CS

- A single Certification System with two Schemes ('A' and 'B')
- Requirements in Scheme A or Scheme B are the same, i.e. compliance with ISO/IEC 17025 and ISO/IEC 17065
- However, evaluation of compliance is different
 - For Scheme A - accreditation or peer assessment
 - For Scheme B - “self-declaration” (with supporting evidence)
- Defined Management Structure, including a dedicated Management Committee and Executive Secretary
- All instruments that fulfill specific requirements will
 - *automatically* be included in OIML-CS in Scheme B
 - *automatic* transition (normally after *two* years) to Scheme A
- Aim for all instrument categories to be in Scheme A



OIML-CS developments

- 37 measuring instrument categories
- Five categories are now in Scheme A
- Remainder will transition over the next two years
- 12 Issuing Authorities, 31 Utilizers and Associates
- Current Management Committee activities:
 - application of ISO/IEC 17065
 - assessment requirements (use of experts)
 - exploring the addition of conformity to type
 - use of logos and conformity markings
 - use of test data from field sites



IEC / OIML Cooperation

- IEC / OIML MoU originally signed in 2011
- IEC support to the development of the OIML-CS
- Several meetings with IECEx representatives since 2016
- Acknowledgement regarding use of IECEx IP in OIML B 18
- Signing of updated MoU at CIML meeting 2018 in Hamburg





IECEX / OIML Cooperation

Decision 2018/65 (ExMC/1436/DL)

The Meeting supported the formation of a Joint Working Group between IECEx and OIML to explore synergies and areas where the two organisations may be able to cooperate with the aim of making use of existing systems and practices in order to reduce cost and time to market for manufacturers of Ex equipment covered by both IECEx and OIML-CS Certification schemes. The terms of reference and proposed membership discussed at this meeting was also endorsed.

Resolution no. 2018/13

(agenda item 9.3.1)

The Committee,

Noting the proposal from the IECEx Management Committee,

Decides to establish a Joint Working Group with the IECEx to explore synergies and opportunities for cooperation,

Requests Dr. Roman Schwartz and Mr. Paul Dixon to represent the OIML on the Joint Working Group, and

Requests the OIML representatives to report to the CIML on the activities of the Joint Working Group at the 54th CIML Meeting in 2019.



IECEX / OIML Cooperation

- Aim: Joint Work Program to explore further opportunities for cooperation between the two organizations - for the benefit of manufacturers dealing with measuring instruments used in Ex environment
 - Joint IECEX / OIML Working Group (JWG) established
 - Telephone meetings between IECEX and OIML-CS Executive Secretaries – Nov '18 and Feb '19
 - Participation of IECEX Executive Secretary in OIML-CS Management Committee Meeting – March '19
 - First meeting of JWG – 25 September 2019



Common Denominators for IEC and OIML

- Level playing field for all parties: producers and conformity assessment bodies
- Promotion of free trade – eliminating technical barriers to trade
- Conformity assessment
- Traceability of measurements
- Minimising costs and work load for the actors on the market
- Achieving market confidence





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